

**Search Notes**

Application/Control No.

09/712,855

Examiner

Christopher A. Revak

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2131

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
714	5,6,16,17	2/16/2005	CR
714	19	2/16/2005	CR
380	44,277	2/16/2005	CR
713/168,176,181- 185,200		2/16/2005	cr

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PG PUB, USOCR	9/9/2005	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	9/9/2005	CR

**Search Notes (continued)**

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Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
707	1,9	2/16/2005	CR
707	200-204	2/16/2005	CR

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR